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ANALOG DEVICES

2Ω Max On Resistance, ±15 V/12 V/±5 V *i*CMOS[™] Dual SPDT Switch

Preliminary Technical Data

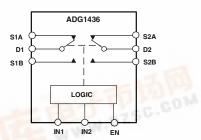
ADG1436



Data aquisition systems Battery-powered systems Sample-and-hold systems **Audio signal routing Communication systems Relay Replacement**



Figure 1.TSSOP package



SWITCHES SHOWN FOR A "1" INPUT LOGIC

Figure 2.LFCSP package

GENERAL DESCRIPTION

The ADG1436 is a monolithic CMOS device containing two independently selectable SPDT switches. An EN input on the LFCSP package is used to enable or disable the device. When disabled, all channels are switched off. Each switch conducts equally well in both directions when on and has an input signal range that extends to the supplies. In the off condition, signal levels up to the supplies are blocked. Both switches exhibit break-before-make switching action for use in multiplexer applications.

It is designed on an iCMOS process. iCMOS (industrial-CMOS) is a modular manufacturing process combining high voltage CMOS (complementary metal-oxide semiconductor) and bipolar technologies. It enables the development of a wide range of high performance analog ICs capable of 33 V operation in a footprint that no previous generation of high voltage parts has been able to achieve. Unlike analog ICs using conventional CMOS processes, iCMOS components can tolerate high supply

Rev-PrODF

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voltages, while providing increased performance, dramatically lower power consumption, and reduced package size.

The on resistance profile is very flat over the full analog input range ensuring excellent linearity and low distortion when switching audio signals. *i*CMOS construction ensures ultralow power dissipation, making the part ideally suited for portable and battery-powered instruments.

PRODUCT HIGHLIGHTS

- 1. 2Q Max On Resistance over temperature.
- 2. Minimum distortion
- 3. 3 V logic-compatible digital inputs: $V_{IH} = 2.0 \text{ V}, V_{IL} = 0.8 \text{ V}.$
- 4. No V_L logic power supply required.
- 5. Ultralow power dissipation: <0.03 µW.
- 16-lead TSSOP and 16-lead 4 mm × 4mm LFCSP 6. packages.

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Preliminary Technical Data

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SPECIFICATIONS

DUAL SUPPLY

 V_{DD} = 15 V \pm 10%, V_{SS} = –15 V \pm 10%, GND = 0 V, unless otherwise noted.

Table 1.

	25°C	-40°C to +85°C	-40°C to +125°C		
ANALOG SWITCH					
Analog Signal Range			V_{DD} to V_{SS}	V	
On Resistance (R _{ON})	1.5			Ωtyp	$V_{s} = \pm 10 V$, $I_{s} = -10 mA$; Figure 23
		2		Ωmax	$V_{DD} = +13.5 \text{ V}, V_{SS} = -13.5 \text{ V}$
On Resistance Match between Channels (ΔR_{ON})	0.1			Ωtyp	$V_{s} = \pm 10 V$, $I_{s} = -10 mA$
		0.5		Ωmax	
On Resistance Flatness (R _{FLAT(ON)})	0.1			Ωtyp	$V_s = -5 V/0 V/+5 V$; $I_s = -10 mA$
		0.5		Ωmax	
LEAKAGE CURRENTS					$V_{DD} = +16.5 \text{ V}, V_{SS} = -16.5 \text{ V}$
Source Off Leakage, Is (Off)	±0.01			nA typ	$V_s = \pm 10 V$, $V_s = \pm 10 V$; Figure 23
<u> </u>	±0.5	±2.5	±5	nA max	······································
Drain Off Leakage, I _D (Off)	±0.01		-	nA typ	$V_{s} = \pm 10 V$, $V_{s} = \pm 10 V$;; Figure 23
	±0.5	±2.5	±5	nA max	
Channel On Leakage, I _D , I _s (On)	±0.04			nA typ	$V_{s} = V_{D} = \pm 10 V$; Figure 23
	±1	±2.5	±5	nA max	
DIGITAL INPUTS				THU THUN	
Input High Voltage, VINH			2.0	V min	
Input Low Voltage, VINH			0.8	V max	
	0.005		0.8		VIN = VINI OF VINH
Input Current, IINL or IINH	0.005		±0.5	μA typ	$\mathbf{v}_{\text{IN}} = \mathbf{v}_{\text{INL}} \mathbf{O} \mathbf{r} \mathbf{v}_{\text{INH}}$
Digital lagest Caracitan as C			±0.5	µA max	
Digital Input Capacitance, C _{IN} DYNAMIC CHARACTERISTICS ¹	5			pF typ	
	100				
Transition Time, t _{TRANS}	120		200	ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$
	150		200	ns max	$V_{s} = +10 V$; Figure 25
t _{on} (EN)	85	100		ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$
	105	130	140	ns max	V _s = 10 V; see Figure 25
t _{off} (EN)	105	150	170	ns typ	$R_L = 300 \Omega, C_L = 35 pF$
Duraly hafave Males Time Dalays t	125	150	170	ns max	$V_s = 10 V;$ see Figure 25
Break-before-Make Time Delay, t _D	15		40	ns typ	$R_L = 300 \Omega, C_L = 35 pF$
			1	ns min	$V_{S1} = V_{S2} = +10$ V; Figure 27
Charge Injection	50			pC typ	$V_s = 0 V, R_s = 0 \Omega, C_L = 1 nF;$ Figure 29
Off Isolation	50			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; Figure 3
Channel-to-Channel Crosstalk	60			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; Figure 3
Total Harmonic Distortion + Noise	0.015			% typ	$R_L = 110\Omega$, 5 V rms, f = 20 Hz to 20 kHz
–3 dB Bandwidth	100			MHz typ	$R_L = 50 \Omega$, $C_L = 5 pF$; Figure 32
Cs (Off)	35			pF typ	$f = 1 MHz; V_s = 0 V$
C _D (Off)	35			pF typ	$f = 1 MHz; V_s = 0 V$
C _D , C _s (On)	70			pF typ	$f = 1 MHz; V_s = 0 V$
POWER REQUIREMENTS					$V_{DD} = +16.5 \text{ V}, V_{SS} = -16.5 \text{ V}$
I _{DD}	0.001			μA typ	Digital Inputs = $0 V \text{ or } V_{DD}$
			1	µA max	
I _{DD}	150			μA typ	Digital Input = 5 V
			300	µA max	
lss	0.001			μA typ	Digital Inputs = $0 V$, $5V \text{ or } V_{DD}$
			1.0	µA max	

	25°C	-40°C to +85°C	-40°C to +125°C		
V _{DD} /V _{SS}			±4.5/±16.5	V min/max	Gnd = 0V

¹ Guaranteed by design, not subject to production test.

SINGLE SUPPLY

 V_{DD} = 12 V \pm 10%, V_{SS} = 0 V, GND = 0 V, unless otherwise noted.

Table 2.

	25°C	-40°C to +85°C	-40°C to +125°C		
ANALOG SWITCH					
Analog Signal Range			$0 V to V_{\text{DD}}$	V	
On Resistance (R _{ON})	2.5			Ωtyp	$V_s = +10 V$, $I_s = -10 mA$; Figure 23
	3	4		Ωmax	_
On Resistance Match between Channels (ΔR _{ON})	0.1			Ωtyp	$V_s = +10 V$, $I_s = -10 mA$
		0.5		Ωmax	
On Resistance Flatness (R _{FLAT(ON)})	0.1	0.5		Ωtyp	$V_s = +3 V/+6 V/+9 V$, $I_s = -10 mA$
LEAKAGE CURRENTS					$V_{DD} = 12 V$
Source Off Leakage, Is (Off)	±0.01			nA typ	$V_{\rm S} = 1 \text{ V}/10 \text{ V}, V_{\rm D} = 10 \text{ V}/1 \text{ V};$ Figure 24
	±0.5	±2.5	±5	nA max	
Drain Off Leakage, I _D (Off)	±0.01			nA typ	$V_{s} = 1 \text{ V}/10 \text{ V}, V_{D} = 10 \text{ V}/1 \text{ V};$ Figure 24
	±0.5	±2.5	±5	nA max	
Channel On Leakage, I _D , I _S (On)	±0.04			nA typ	$V_{s} = V_{D} = 1 V \text{ or } 10 V$, Figure 25
	±1	±2.5	±5	nA max	
DIGITAL INPUTS					
Input High Voltage, V _{INH}			2.0	V min	
Input Low Voltage, VINL			0.8	V max	
Input Current, I _{INL} or I _{INH}	0.001			μA typ	VIN = VINI OF VINH
···			±0.5	µA max	
Digital Input Capacitance, C _{IN}	5			pF typ	
DYNAMIC CHARACTERISTICS ¹				. ,.	
Transition Time, trrans	120			ns typ	$R_L = 300 \Omega, C_L = 35 pF$
	150		200	ns max	$V_s = 8 V$; Figure 25
t _{on} (EN)	85			ns typ	$R_{L} = 300 \Omega, C_{L} = 35 pF$
	105	130	140	ns max	$V_s = 8 V$; Figure 25
t _{off} (EN)	105			ns typ	$R_{L} = 300 \Omega, C_{L} = 35 pF$
	125	150	170	ns max	$V_s = 8 V$; Figure 25
Break-before-Make Time Delay, t _D	15			ns typ	$R_L = 300 \Omega, C_L = 35 pF$
			1	ns min	$V_{s1} = V_{s2} = 8 V$; Figure 27
Charge Injection	30			pC typ	$V_s = 6 V, R_s = 0 \Omega, C_L = 1 nF;$ Figure 29
Off Isolation	50			dB typ	$R_{L} = 50 \Omega, C_{L} = 5 pF, f = 1 MHz;$ Figure 30
Channel-to-Channel Crosstalk	60			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; Figure 31
Total Harmonic Distortion + Noise	0.015			% typ	$R_L = 110\Omega$, 5 V rms, f = 20 Hz to 20 kHz
–3 dB Bandwidth	100			MHz typ	$R_L = 50 \Omega$, $C_L = 5 pF$; Figure 32
Cs (Off)	35			pF typ	$f = 1 MHz; V_s = 6V$
C_{D} (Off)	35			pF typ	$f = 1 MHz; V_s = 6V$
C _D , C _s (On)	70			pF typ	$f = 1 MHz; V_s = 6 V$

	25°C	-40°C to +85°C	-40°C to +125°C		
POWER REQUIREMENTS					V _{DD} = 13.2 V
IDD	0.001			μA typ	Digital Inputs = 0 V or V _{DD}
			1.0	μA max	
IDD	150			μA typ	Digital Inputs = 5 V
			300	μA max	
V _{DD}			5/16.5	V	Gnd = 0V, Vss = 0V
				min/max	

¹ Guaranteed by design, not subject to production test.

DUAL SUPPLY

 V_{DD} = 5 V \pm 10%, V_{SS} = -5 V \pm 10%, GND = 0 V, unless otherwise noted.

Table 3.

	25°C	−40°C to +85°C	−40°C to +125°C	Unit	Test Conditions/Comments
ANALOG SWITCH					
Analog Signal Range			0 V to VDD	v	
On Resistance (R _{ON})	3			Ωtyp	$V_s = \pm 3.3V$, $I_s = -10$ mA; See figure x
		4		Ω max	$V_{DD} = +4.5 \text{ V}, \text{ V}_{SS} = -4.5 \text{ V}$
On Resistance Match Between Channels (ΔR_{ON})	0.1			Ωtyp	$V_s = \pm 3.3 \text{ V}$, $I_s = -10 \text{ mA}$
				Ωmax	
On Resistance Flatness (R _{FLAT(ON)})	0.1			Ωtyp	$V_s = -3 V/0 V/+3 V; I_s = -10 mA$
LEAKAGE CURRENTS					$V_{DD} = +5.5 V, V_{SS} = -5.5 V$
Source Off Leakage, Is (Off)	±0.01			nA typ	$V_s = \pm 4.5 \text{ V}, V_D = \mp 4.5 \text{ V};$ See figure x
	±0.5	±2.5	±5	nA max	
Drain Off Leakage, I⊳ (Off)	±0.01			nA typ	$V_{S} = \pm 4.5 \text{ V}, V_{D} = \mp 4.5 \text{ V}; \text{ See figure x}$
(0,0,0,0)	±0.5	±2.5	±5	nA max	$v_5 - \pm 4.5 v, v_0 - +4.5 v;$ see ligure x
Channel On Leakage, I _D , I _s (On)	±0.5 ±0.04	2.2		nA max nA typ	$V_{s} = V_{D} = \pm 4.5V$; See figure x
	±0.04 ±1	±5	±5	nA max	$v_{\rm S} = v_{\rm D} = \pm 4.5 v$, see figure x
DIGITAL INPUTS	<u> </u>	<u>+</u> 5	±5	пл пал	
Input High Voltage, VINH			2.0	V min	
Input Low Voltage, VINH			0.8	V max	
Input Current, Inlor Inh	0.001		0.0	μA typ	V _{IN} = V _{INI} or V _{INH}
	0.001		±0.5	µA max	
Digital Input Capacitance, C _№	3		_0.5	pF typ	
DYNAMIC CHARACTERISTICS ¹	-			P: 7P	
Transition Time, t _{TRANS}	150			ns typ	$R_L = 300 \Omega, C_L = 35 pF$
	190		265	ns max	$V_s = 3 V$; Figure 25
t _{on} (EN)	85			ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$
	105	130	140	ns max	V _s = 3 V; Figure 25
t _{off} (EN)	105			ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$
	125	150	170	ns max	$V_s = 3 V$; Figure 25
Break-Before-Make Time Delay, t⊳	50			ns typ	$R_L = 300 \Omega, C_L = 35 pF$
			10	ns min	$V_{s1} = V_{s2} = 3 V$; See figure 25
Charge Injection	50			pC typ	$V_s = 0 V$, $R_s = 0 \Omega$, $C_L = 1 nF$; See figure x
Off Isolation	50			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; See figur
Channel-to-Channel Crosstalk	60			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; See figur

Preliminary Technical Data

		−40°C to	−40°C to		
	25°C	+85°C	+125°C	Unit	Test Conditions/Comments
Total Harmonic Distortion + Noise	0.002			% typ	$R_L = 110\Omega$, 5 V pp, f = 20 Hz to 20 kHz
−3 dB Bandwidth	200			MHz typ	$R_L = 50 \Omega$, $C_L = 5 pF$; See figure x
Cs (Off)	35			pF typ	Vs = 0V, f = 1 MHz
C _D (Off)	35			pF typ	Vs = 0V, f = 1 MHz
C _D , C _s (On)	150			pF typ	Vs = 0V, f = 1 MHz
POWER REQUIREMENTS					$V_{DD} = 5.5 V$, $Vss = -5.5 V$
lod	0.001			μA typ	Digital inputs = $0 V \text{ or } V_{DD}$
			1.0	μA max	
lss	0.001			μA typ	Digital inputs = $0 V \text{ or } V_{DD}$
			1.0	μA max	
V _{DD} /V _{SS}			±4.5/±16.5	V	Gnd = 0V
				min/max	

¹ Guaranteed by design, not subject to production test.

ABSOLUTE MAXIMUM RATINGS

 $T_A = 25^{\circ}$ C, unless otherwise noted.

Table 4.

Parameter	Ratings
V _{DD} to V _{SS}	35 V
V _{DD} to GND	–0.3 V to +25 V
Vss to GND	+0.3 V to -25 V
Analog Inputs ¹	$V_{SS} - 0.3 \text{ V}$ to $V_{DD} + 0.3 \text{ V}$
Digital Inputs ¹	GND – 0.3 V to V _{DD} + 0.3 V or 30 mA, whichever occurs first
Peak Current, S or D	300 mA (pulsed at 1 ms, 10% duty cycle max)
Continuous Current, S or D	200 mA
Operating Temperature Range	
Automotive (Y Version)	-40°C to +125°C
Storage Temperature Range	–65°C to +150°C
Junction Temperature	150°C
16-Lead TSSOP, θ _{JA} Thermal Impedance	150.4°C/W
16-Lead LFCSP, θ _{JA} Thermal Impedance	72.7°C/W
Reflow Soldering Peak Temperature, Pb free	260°C

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other condition s above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

¹ Over voltages at IN, S, or D are clamped by internal diodes. Current should be limited to the maximum ratings given.

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although this product features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



PIN CONFIGURATIONS AND FUNCTION DESCRIPTIONS

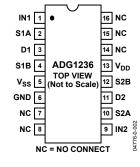


Figure 3.TSSOP Pin Configuration

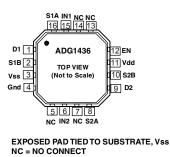


Figure 4. LFCSP Pin Configuration

Table 5. Pin Function Descriptions

Pin No.			
TSSOP	LFCSP	Mnemonic	Function
1	15	IN1	Logic Control Input.
2	16	S1A	Source Terminal. Can be an input or output.
3	1	D1	Drain Terminal. Can be an input or output.
4	2	S1B	Source Terminal. Can be an input or output.
5	3	Vss	Most Negative Power Supply Potential.
6	4	GND	Ground (0 V) Reference.
7, 8, 14–16	5,7,13,14	NC	No Connect.
9	6	IN2	Logic Control Input.
10	8	S2A	Source Terminal. Can be an input or output.
11	9	D2	Drain Terminal. Can be an input or output.
12	10	S2B	Source Terminal. Can be an input or output.
13	11	V _{DD}	Most Positive Power Supply Potential.
-	12	EN	Active High Digital Input. When low, the device is disabled and all switches are off. When high, INx logic inputs determine the on switches.

TRUTH TABLE FOR SWITCHES

Table 6. ADG1436 TSSOP Truth Table

INx	Switch xA	Switch xB
0	Off	On
1	On	Off

Table 7. ADG1436 LFCSPTruth Table

EN	INx	SxA	SxB
0	Х	Off	Off
1	0	Off	On
1	1	On	Off

ADG1436

TERMINOLOGY

I_{DD}

The positive supply current. Iss

The negative supply current.

 $\mathbf{V}_{D}\left(\mathbf{V}_{S}\right)$ The analog voltage on Terminals D and S.

R_{ON} The ohmic resistance between D and S.

R_{FLAT(ON)} Flatness is defined as the difference between the maximum and

minimum value of on resistance, as measured over the specified analog signal range.

Is (Off) The source leakage current with the switch off.

I_D (Off) The drain leakage current with the switch off.

 $I_{\rm D},\,I_{\rm S}\left(On\right)$ The channel leakage current with the switch on.

 $V_{\mbox{\scriptsize INL}}$ The maximum input voltage for Logic 0.

 $V_{\mbox{\scriptsize INH}}$ The minimum input voltage for Logic 1.

I_{INL} (I_{INH}) The input current of the digital input.

 C_{s} (Off) The off switch source capacitance, measured with reference to ground. C_D (Off) The off switch drain capacitance, measured with reference to ground.

 C_D , C_S (On) The on switch capacitance, measured with reference to ground.

C_{IN} The digital input capacitance.

 t_{TRANS} The delay time between the 50% and 90% points of the digital input and switch on condition when switching from one address state to another.

Charge Injection A measure of the glitch impulse transferred from the digital input to the analog output during switching.

Off Isolation A measure of unwanted signal coupling through an off switch. Crosstalk

A measure of unwanted signal that is coupled through from one channel to another as a result of parasitic capacitance.

Bandwidth The frequency at which the output is attenuated by 3 dB.

On Response The frequency response of the on switch.

Insertion Loss The loss due to the on resistance of the switch.

THD + N The ratio of the harmonic amplitude plus noise of the signal to the fundamental.

TYPICAL PERFORMANCE CHARACTERISTICS



Figure 5. On Resistance as a Function of V_D (V_S) for Dual Supply



Figure 6, On Resistance as a Function of V_D (V_s) for Single I Supply



Figure 7. On Resistance as a Function of $V_{\rm D}\,(V_{\rm S})$ for Different Temperatures, Dual Supply



Figure 8. On Resistance as a Function of $V_{\rm D}$ (Vs) for Different Temperatures, Single Supply

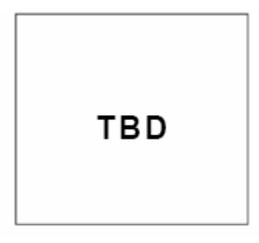


Figure 9. Leakage Current as a Function of $V_D(V_S)$



Figure 10. Leakage Currents as a Function of V_D (V_S)

ADG1436

Figure 11. Leakage Current as a Function of V_D (V_S)



Figure 12. Leakage Currents as a Function of Temperature



Figure 13. IDD vs. Logic Level

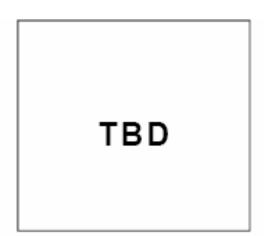




Figure 15. Charge Injection vs. Source Voltage



Figure 16. t_{TRANSITION} Times vs. Temperature



Figure 14. Logic Threshold Voltage vs Supply Voltage

Figure 17. Off Isolation vs. Frequency





Figure 20. THD + N vs. Frequency

Figure 211. Capacitance vs. Source Voltage for Dual Supply Figure 222. Capacitance vs. Source Voltage for Single Supply

Figure 18. Crosstalk vs. Frequency



Figure 19. On Response vs. Frequency

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TEST CIRCUITS

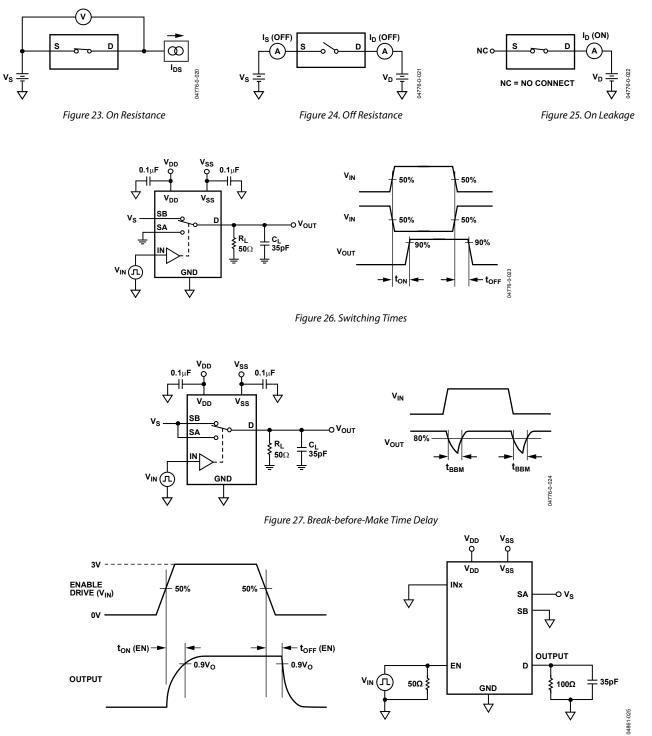


Figure 28. . Enable Delay, ton (EN), toff (EN)

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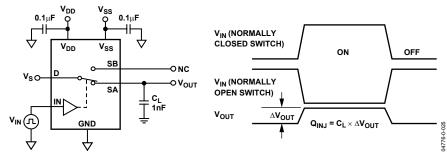


Figure 29. Charge Injection

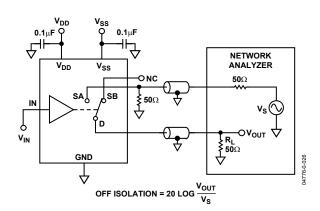


Figure 30. Off Isolation

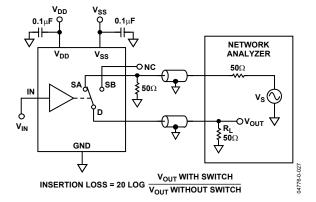


Figure 31. Channel-to-Channel Crosstalk

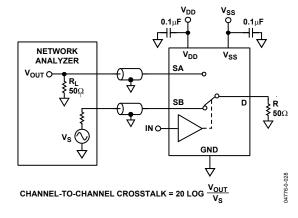
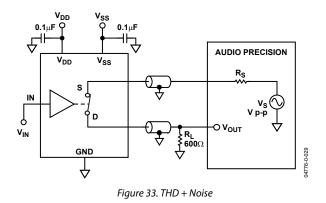


Figure 32. Bandwidth



OUTLINE DIMENSIONS

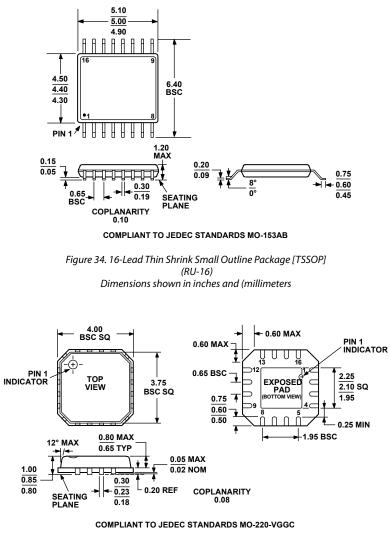


Figure 35. 16-Lead Lead Frame Chip Scale Package [VQ_LFCSP] 4 mm × 4 mm Body, Very Thin Quad (CP-16-4) Dimensions shown in millimeters

ORDERING GUIDE

Model	Temperature Range	Package Description	Package Option
ADG1436YRUZ	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1436YRUZ- REEL	–40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1436YRUZ- REEL7	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-16
ADG1436YCPZ- 500RL7	-40°C to +125°C	Lead Frame Chip Scale Package (LFCSP)	CP-16-4
ADG1436YCPZ- REEL7	-40°C to +125°C	Lead Frame Chip Scale Package (LFCSP)	CP-16-4

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